Notice of References Cited Examiner Art Un

10/561,894 Reexamination
GRUNDL ET AL.

Examiner Art Unit

2834

Applicant(s)/Patent Under

Page 1 of 1

THANH LAM

Application/Control No.

	U.S. PATENT DOCUMENTS							
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification			
*	Α	US-2005/0248228 A1	11-2005	Yoneda et al.	310/179			
*	В	US-2005/0236921 A1	10-2005	Yoneda et al.	310/179			
*	С	US-2002/0053853 A1	05-2002	Nishimura, Shinji	310/201			
*	D	US-3,761,754 A	09-1973	Boesel, Walter F.	310/218			
*	Е	US-2004/0232779 A1	11-2004	Arimitsu et al.	310/043			
*	F	US-6,838,790 B2	01-2005	Arimitsu et al.	310/43			
*	G	US-5,332,939 A	07-1994	Fanning et al.	310/71			
*	Н	US-4,329,609 A	05-1982	Allegre et al.	310/183			
*	Т	US-3,885,302 A	05-1975	Boesel, Walter F.	29/596			
	J	US-						
	к	US-						
	L	US-						
	М	US-						

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

NON-PATENT DOCUMENTS						
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	v					
	w					
	×					

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.